FAIRCHILD SEMICONDUCTOR®

October 2006

FDZ191P
P-Channel 1.5V PowerTrench™ WL-CSP MOSFET
-20V, -1A, 85mΩ

Features

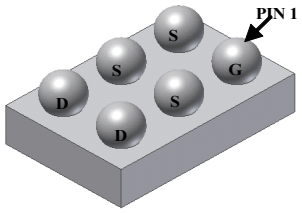
- Max $r_{DS(on)}$ = 85mΩ at V_{GS} = -4.5V, I_D = -1A
- Max $r_{DS(on)}$ = 123mΩ at V_{GS} = -2.5V, I_D = -1A
- Max $r_{DS(on)}$ = 200mΩ at V_{GS} = -1.5V, I_D = -1A
- Occupies only 1.5 mm^2 of PCB area Less than 50% of the area of 2 x 2 BGA
- Ultra-thin package: less than 0.65 mm height when mounted to PCB
- RoHS Compliant

General Description

Designed on Fairchild's advanced 1.5V PowerTrench process with state of the art "low pitch" WLCSP packaging process, the FDZ191P minimizes both PCB space and $r_{DS(on)}$. This advanced WLCSP MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, ultra-low profile packaging, low gate charge, and low $r_{DS(on)}$. .

Application

- Battery management
- Load switch
- Battery protection



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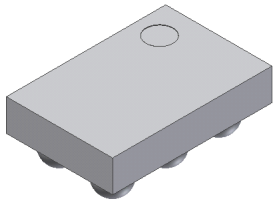

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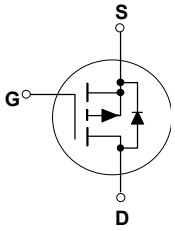


MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V_{DS}	Drain to Source Voltage			-20	V
V_{GS}	Gate to Source Voltage			±8	V
I_D	Drain Current -Continuous	T_A = 25°C	(Note 1a)	-3	A
	-Pulsed			-15	
P_D	Power Dissipation	T_A = 25°C	(Note 1a)	1.5	W
	Power Dissipation	T_A = 25°C	(Note 1b)	0.9	
T_J, T_{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Case	(Note 1a)	83	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	140	

Package Marking and Ordering Information

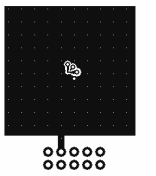
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
1	FDZ191P	WL-CSP	7”	8mm	5000 units

Electrical Characteristics T_J = 25°C unless otherwise noted

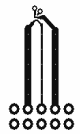
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = -250μA, V_{GS} = 0V	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = -250μA, referenced to 25°C		-12		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = -16V, V_{GS} = 0V			-1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±8V, V_{DS} = 0V			±100	nA
On Characteristics						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = -250μA	-0.4	-0.6	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250μA, referenced to 25°C		2		mV/°C
$r_{DS(on)}$	Drain to Source On Resistance	V_{GS} = -4.5V, I_D = -1A		67	85	mΩ
		V_{GS} = -2.5V, I_D = -1A		85	123	
		V_{GS} = -1.5V, I_D = -1A		140	200	
		V_{GS} = -4.5V, I_D = -1A T_J = 125°C		87	123	
$I_{D(on)}$	On to State Drain Current	V_{GS} = -4.5V, V_{DS} = -5V	-10			A
g_{FS}	Forward Transconductance	V_{DS} = -5V, I_D = -1A		7		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = -10V, V_{GS} = 0V, f = 1MHz		800		pF
C_{oss}	Output Capacitance			155		pF
C_{rss}	Reverse Transfer Capacitance			90		pF
R_g	Gate Resistance	f = 1MHz		9		Ω
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = -10V, I_D = -1A, V_{GS} = -4.5V, R_{GEN} = 6Ω		11	20	ns
t_r	Rise Time			10	20	ns
$t_{d(off)}$	Turn-Off Delay Time			50	80	ns
t_f	Fall Time			30	48	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V	V_{GS} = 0V to 10V, V_{DD} = -10V, I_D = -1A		9	13	nC
Q_{gs}	Gate to Source Gate Charge			1		nC
Q_{gd}	Gate to Drain “Miller” Charge			2		nC
Drain-Source Diode Characteristics						
I_S	Maximum continuous Drain-Source Diode Forward Current				-1.1	A
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0V, I_S = -1.1A (Note 2)		-0.7	-1.2	V
t_{rr}	Reverse Recovery Time	I_F = -1A, di/dt = 100A/μs		21		ns
Q_{rr}	Reverse Recovery Charge			5		nC

Notes:

1: $R_{\theta JA}$ is determined with the device mounted on a 1in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. The thermal resistance from the junction to the circuit board side of the solder ball, $R_{\theta JB}$ is defined for reference. For $R_{\theta JC}$ the thermal reference point for the case is defined as the top surface of the copper chip carrier. $R_{\theta JC}$ and $R_{\theta JB}$ are guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.



a. 83°C/W when mounted on a 1 in^2 pad of 2 oz copper,1.5” X 1.5” X 0.062” thick PCB



b. 140°C/W when mounted on a minimum pad of 2 oz copper

2: Pulse Test: Pulse Width < 300μs, Duty cycle < 2.0%.

Typical Characteristics T_J = 25°C unless otherwise noted

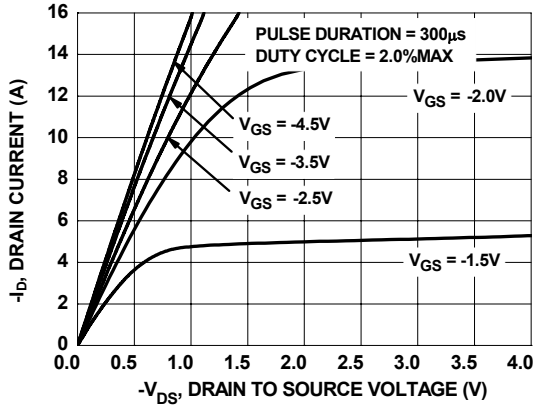


Figure 1. On Region Characteristics

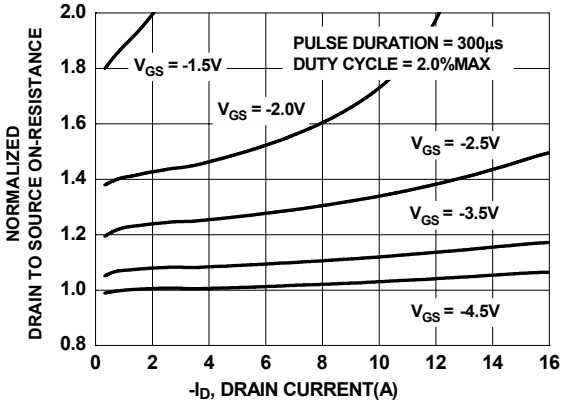


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

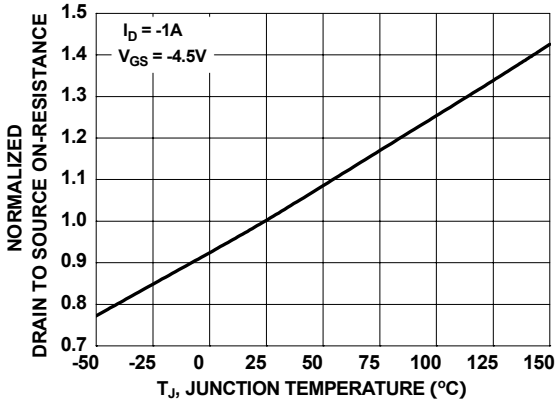


Figure 3. Normalized On Resistance vs Junction Temperature

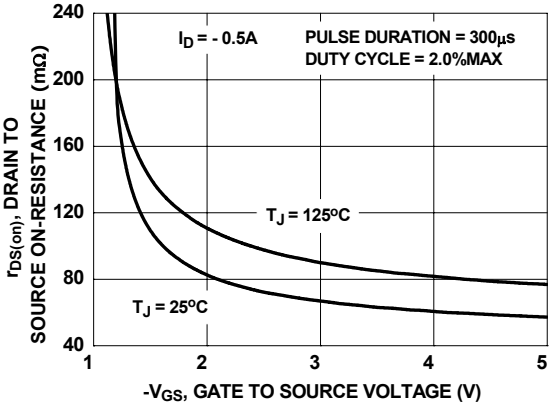


Figure 4. On-Resistance vs Gate to Source Voltage

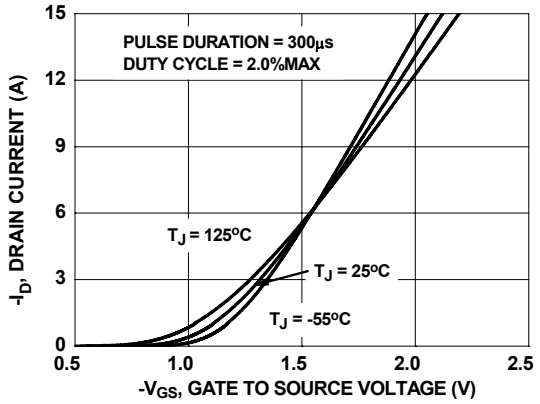


Figure 5. Transfer Characteristics

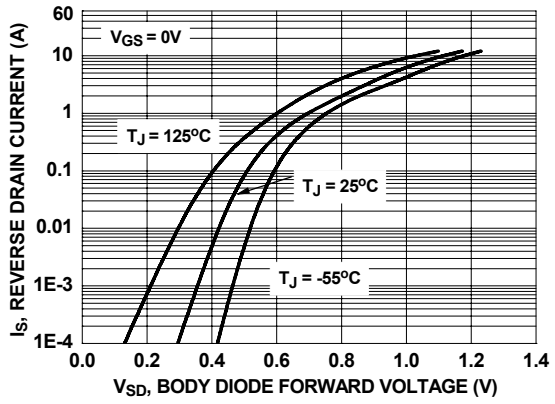


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

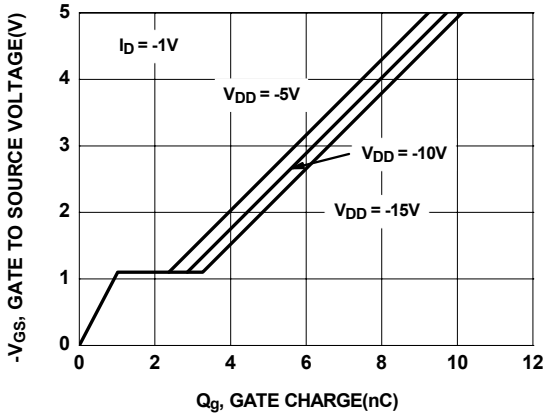


Figure 7. Gate Charge Characteristics

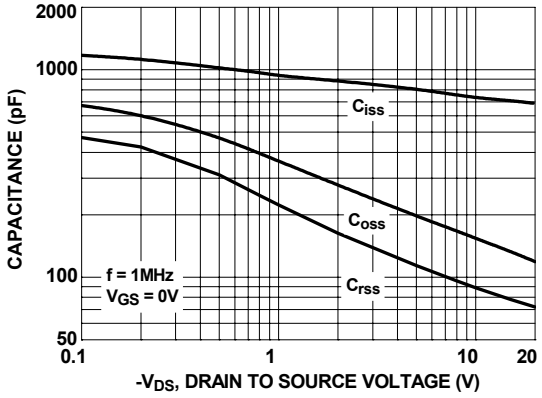


Figure 8. Capacitance vs Drain to Source Voltage

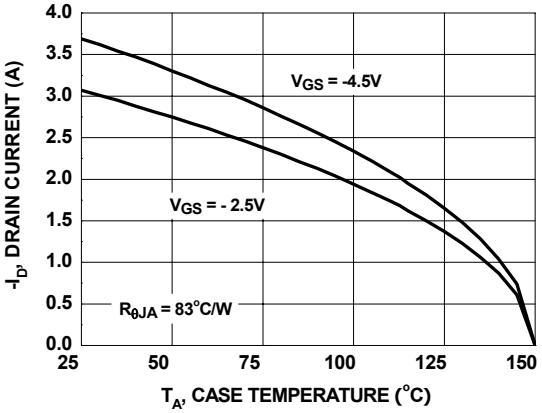


Figure 9. Maximum Continuous Drain Current vs Ambient Temperature

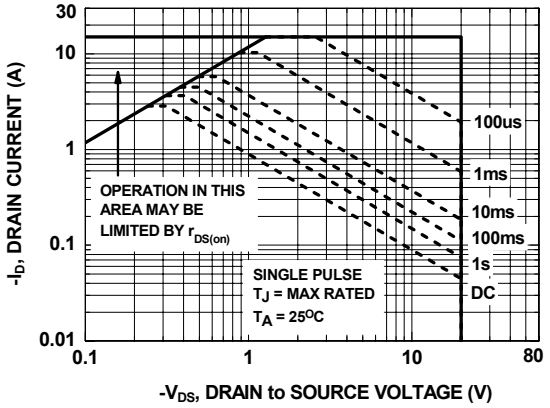


Figure 10. Forward Bias Safe Operating Area

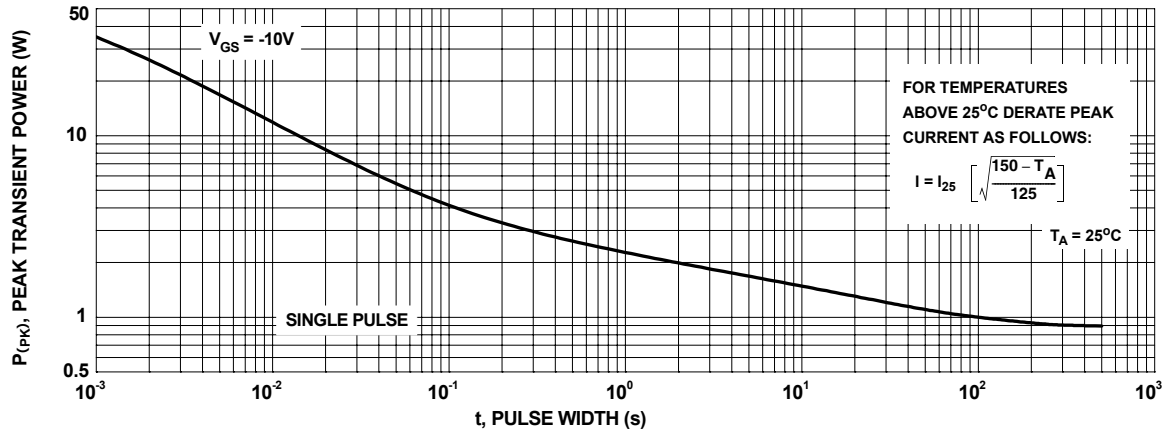


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25°C unless otherwise noted

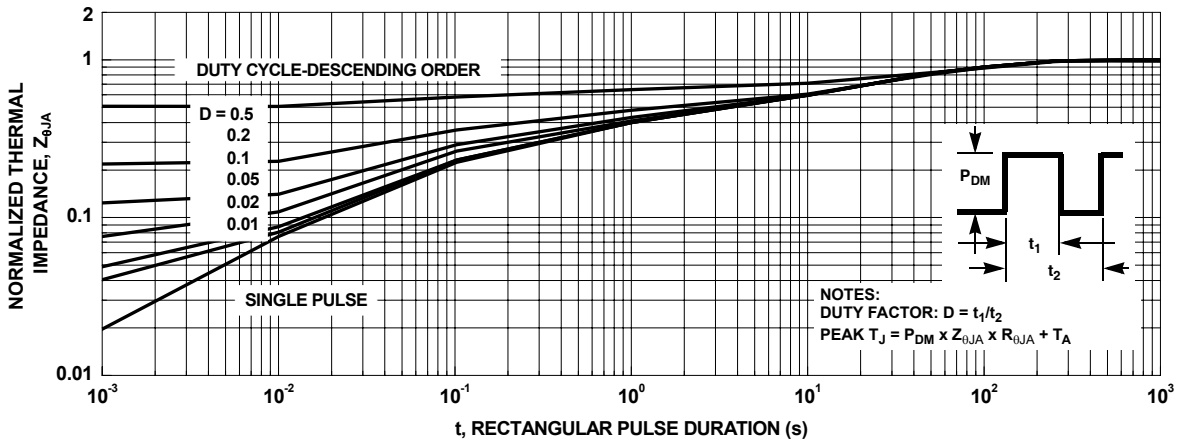
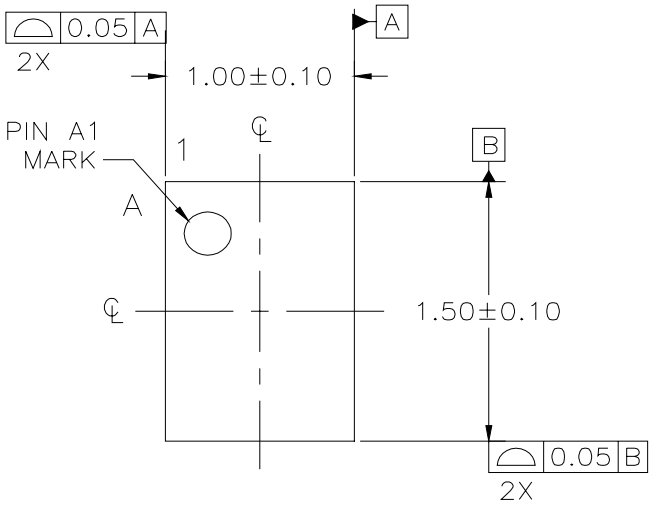
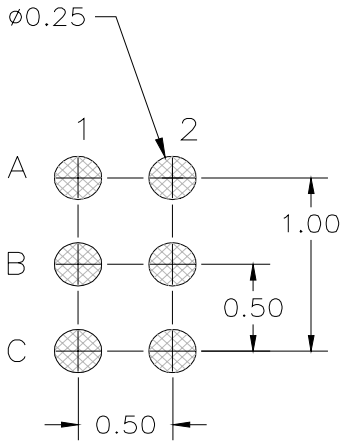
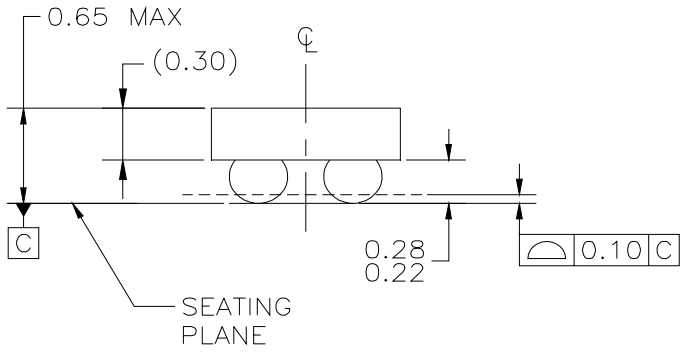


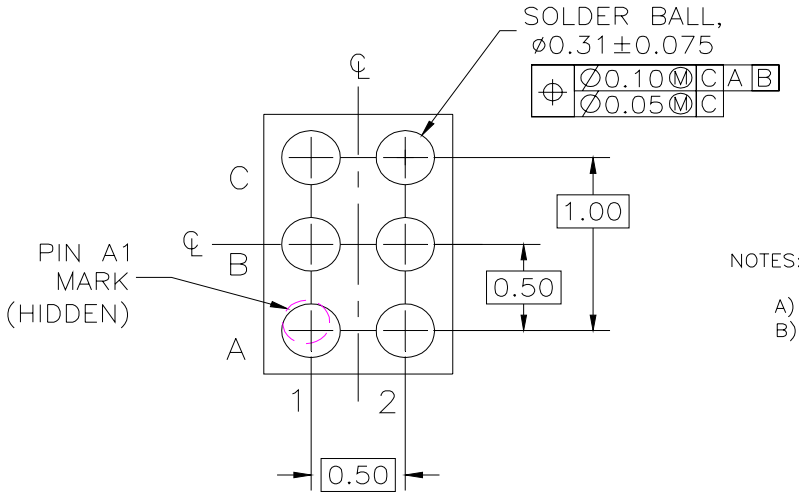
Figure 12. Transient Thermal Response Curve





LAND PATTERN
RECOMMENDATION





NOTES: UNLESS OTHERWISE SPECIFIED

A) ALL DIMENSIONS ARE IN MILLIMETERS.
B) NO JEDEC REGISTRATION REFERENCE AS OF OCTOBER 2005.

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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

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